

Maximum Ratings (@ $T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	60	V
Gate-Source Voltage			Vgss	±20	V
Continuous Drain Current (Note 6) V _{GS} = 10V	Steady State	T _A = +25°C T _A = +70°C	I _D	10.4 8.4	А
Maximum Continuous Body Diode Forward Current (Note 6)			ls	10	А
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)			I _{DM}	65	А
Avalanche Current, L = 0.3mH			las	15.8	Α
Avalanche Energy, L = 0.3mH			Eas	37.5	mJ

Thermal Characteristics ($@T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	T _A = +25°C	PD	1.2	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	RθJA	106	°C/W
Total Power Dissipation (Note 6)	T _A = +25°C	PD	1.84	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	68	°C/W
Thermal Resistance, Junction to Case (Note 6)		Rejc	9.2	°C/W
Operating and Storage Temperature Range		TJ, TSTG	-55 to +150	°C

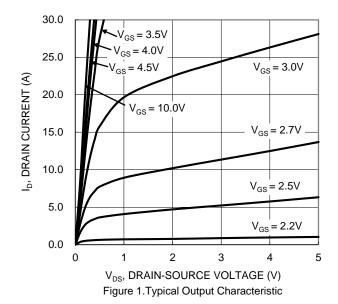
Electrical Characteristics (TA = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	60			V	$V_{GS} = 0V, I_D = 1mA$
Zero Gate Voltage Drain Current	IDSS		_	1	μΑ	V _{DS} = 48V, V _{GS} = 0V
Gate-Source Leakage	Igss	l	_	±10	μΑ	$V_{GS} = \pm 20V$, $V_{DS} = 0V$
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	0.7	_	2	V	$V_{DS}=V_{GS},\ I_D=250\mu A$
Static Drain-Source On-Resistance	-		8.4	11	mΩ	$V_{GS} = 10V, I_D = 10A$
Static Dialit-Source Off-Resistance	RDS(ON)		11.5	14		$V_{GS} = 4.5V, I_{D} = 5A$
Diode Forward Voltage	VsD		0.8	1.2	V	V _G S = 0V, I _S = 20A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	l	1522	l		V _{DS} = 30V, V _{GS} = 0V, f = 1MHz
Output Capacitance	Coss		352		pF	
Reverse Transfer Capacitance	Crss	1	27.5	-		
Gate Resistance	Rg	l	1.4	l	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$
Total Gate Charge (VGS = 4.5V)	Qg	l	10.7	l		V _{DS} = 30V, I _D = 10A
Total Gate Charge (V _{GS} = 10V)	Q_g		22.2		nC	
Gate-Source Charge	Qgs	l	3.3	l	IIC	
Gate-Drain Charge	Q_{gd}		4.2			
Turn-On Delay Time	t _{D(ON)}	_	4.4	_		$V_{GS} = 10V, V_{DS} = 30V,$ $R_{G} = 6\Omega, I_{D} = 10A$
Turn-On Rise Time	t _R	_	6.7	_	no	
Turn-Off Delay Time	tD(OFF)		25.5	_	ns	
Turn-Off Fall Time	tF	l	12.5			
Body Diode Reverse Recovery Time	trr	1	25.8	1	ns	I_ 10 A di/dt 100 A / v o
Body Diode Reverse Recovery Charge	Qrr	_	15.1	_	nC	IF = 10A, di/dt = 100A/μs

Notes:

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
- 6. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
- 7. Short duration pulse test used to minimize self-heating effect.
- 8. Guaranteed by design. Not subject to product testing.





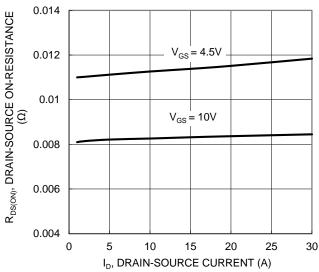
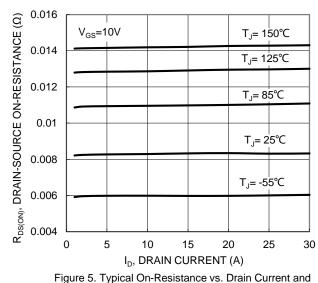
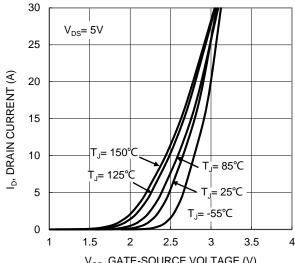


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage



Temperature



V_{GS}, GATE-SOURCE VOLTAGE (V) Figure 2. Typical Transfer Characteristic

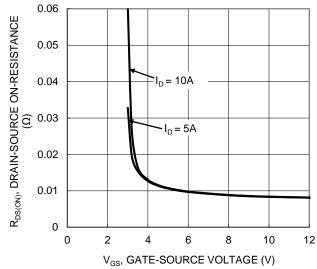


Figure 4. Typical Transfer Characteristic

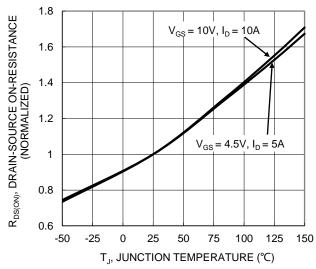


Figure 6. On-Resistance Variation with Temperature



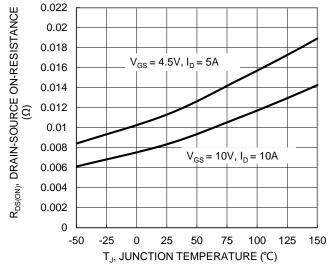


Figure 7. On-Resistance Variation with Temperature

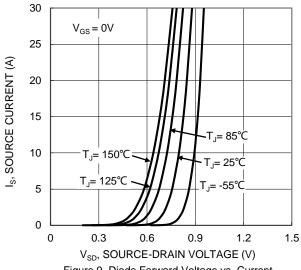


Figure 9. Diode Forward Voltage vs. Current

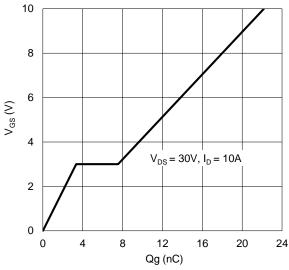


Figure 11. Gate Charge

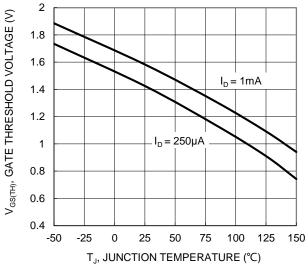
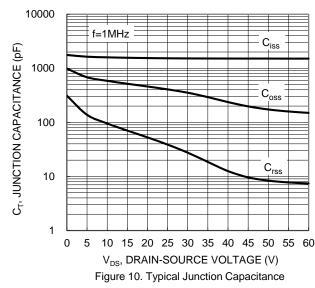


Figure 8. Gate Threshold Variation vs. JunctionTemperature



100 ID, DRAIN CURRENT (A) 10 =10ms T_{J(MAX)}=150°C P_w=100ms T_C=25°C 0.1 Single Pulse DUT on 1*MRP board V_{GS}=10V 0.01 0.01 0.1 10 100 V_{DS}, DRAIN-SOURCE VOLTAGE (V) Figure 12. SOA, Safe Operation Area



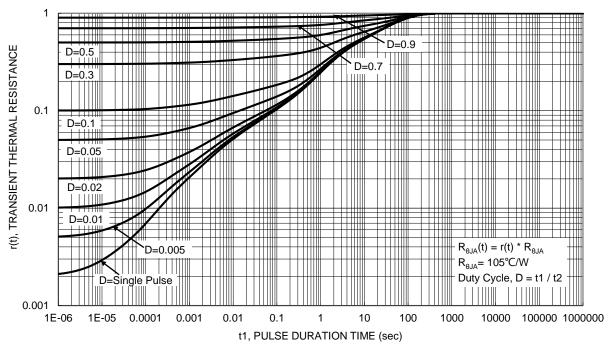


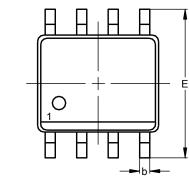
Figure 13. Transient Thermal Resistance

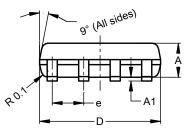


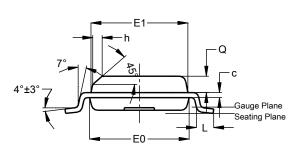
Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.







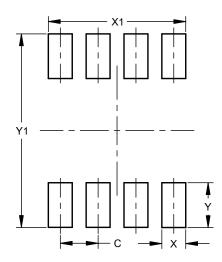


SO-8					
Dim	Min	Max	Тур		
Α	1.40	1.50	1.45		
A1	0.10	0.20	0.15		
b	0.30	0.50	0.40		
С	0.15	0.25	0.20		
D	4.85	4.95	4.90		
Е	5.90	6.10	6.00		
E1	3.80	3.90	3.85		
E0	3.85	3.95	3.90		
е			1.27		
h			0.35		
L	0.62	0.82	0.72		
Q	0.60	0.70	0.65		
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



Dimensions	Value (in mm)
С	1.27
Х	0.802
X1	4.612
Υ	1.505
Y1	6.50



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